

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1	("6528219").PN.	USPAT	OR	OFF	2005/07/21 18:21
L2	499	wafer adj3 error	USPAT	OR	OFF	2005/07/21 18:22
L3	0	2 and (field-mean adj3 error)	USPAT	OR	OFF	2005/07/21 18:22
L4	0	(field-mean adj3 error)	USPAT	OR	OFF	2005/07/21 18:22
L5	6987	(mean adj3 error)	USPAT	OR	OFF	2005/07/21 18:22
L6	4	5 and 2	USPAT	OR	OFF	2005/07/21 18:24
L7	1243	(430/30).CCLS.	USPAT	OR	OFF	2005/07/21 18:25
L8	729	7 and wafer	USPAT	OR	OFF	2005/07/21 18:25
L9	348	8 and error	USPAT	OR	OFF	2005/07/21 18:25
L10	49	9 and residual	USPAT	OR	OFF	2005/07/21 19:12
L11	0	(over adj3 lay adj3 sites)	USPAT	OR	OFF	2005/07/21 18:50
L12	0	(over adj3 lay adj3 sites)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/07/21 18:51
L13	39	(overlay adj3 sites)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/07/21 18:51
L14	36	13 and field	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/07/21 18:51
L15	149	(Field adj3 image adj3 alignment)	USPAT	OR	OFF	2005/07/21 19:12
L16	154	(Field adj3 image adj3 alignment)	USPAT	OR	ON	2005/07/21 19:12
L17	0	16 and (field-to-field)	USPAT	OR	ON	2005/07/21 19:13
L18	154	16 and (field samefield)	USPAT	OR	ON	2005/07/21 19:13
L19	154	16 and (field same field)	USPAT	OR	ON	2005/07/21 19:13
L20	0	16 and (field adj to adj field)	USPAT	OR	ON	2005/07/21 19:13
L21	17	16 and (residual adj3 error)	USPAT	OR	ON	2005/07/21 19:23
L22	674	703/6	USPAT	OR	OFF	2005/07/21 19:24
L23	34	22 and residual and error	USPAT	OR	OFF	2005/07/21 19:24

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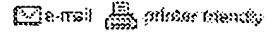
## » Key

IEEE JNL	IEEE Journal or Magazine
IEE JNL	IEE Journal or Magazine
IEEE CNF	IEEE Conference Proceeding
IEE CNF	IEE Conference Proceeding
IEEE STD	IEEE Standard

- ☐ **1. Rain field and reflectivity vertical profile reconstruction from C-band Radar volumetric data**  
Marzano, F.S.; Vulpiani, G.; Picciotti, E.;  
Geoscience and Remote Sensing, IEEE Transactions on  
Volume 42, Issue 5, May 2004 Page(s):1033 - 1046  
Digital Object Identifier 10.1109/TGRS.2003.820313  
[AbstractPlus](#) | Full Text: [PDF\(896 KB\)](#) IEEE JNL
- ☐ **2. Inverse calculations in EEG source analysis applying the finite difference method, reciprocity and lead fields**  
Vanrumste, B.; Van Hoey, G.; Boon, P.; D'Have, M.; Lemahieu, I.;  
Engineering in Medicine and Biology Society, 1998. Proceedings of the 20th Annual  
International Conference of the IEEE  
Volume 4, 29 Oct.-1 Nov. 1998 Page(s):2112 - 2115 vol.4  
Digital Object Identifier 10.1109/IEMBS.1998.747025  
[AbstractPlus](#) | Full Text: [PDF\(404 KB\)](#) IEEE CNF
- ☐ **3. Interpolation of multidimensional random processes with application to fluid flow**  
Zhong, J.; Adrian, R.J.; Huang, T.S.;  
Acoustics, Speech, and Signal Processing, 1993. ICASSP-93., 1993 IEEE International  
Conference on  
Volume 5, 27-30 April 1993 Page(s):181 - 184 vol.5  
Digital Object Identifier 10.1109/ICASSP.1993.319777  
[AbstractPlus](#) | Full Text: [PDF\(256 KB\)](#) IEEE CNF
- ☐ **4. Event-averaged maximum likelihood estimation and mean-field theory in multitarget tracking**  
Kastella, K.;  
Automatic Control, IEEE Transactions on  
Volume 40, Issue 6, June 1995 Page(s):1070 - 1074  
Digital Object Identifier 10.1109/9.388686  
[AbstractPlus](#) | Full Text: [PDF\(504 KB\)](#) IEEE JNL
- ☐ **5. Current dipole localization with an ideal magnetometer system**  
Lutkenhoner, B.;  
Biomedical Engineering, IEEE Transactions on  
Volume 43, Issue 11, Nov. 1996 Page(s):1049 - 1061  
Digital Object Identifier 10.1109/10.541247  
[AbstractPlus](#) | [References](#) | Full Text: [PDF\(1184 KB\)](#) IEEE JNL
- ☐ **6. Classifier fusion results using various open literature data sets**  
Lynch, R.S., Jr.; Willett, P.K.;  
Systems, Man and Cybernetics, 2003. IEEE International Conference on  
Volume 1, 5-8 Oct. 2003 Page(s):723 - 728 vol.1  
Digital Object Identifier 10.1109/ICSMC.2003.1243900

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IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

- ☐ 1. **Characteristic impedance extraction using calibration comparison**  
Vandenberghe, S.; Schreurs, D.M.M.-P.; Carchon, G.; Nauwelaers, B.K.J.C.; De Raedt, W.;  
Microwave Theory and Techniques, IEEE Transactions on  
Volume 49, Issue 12, Dec. 2001 Page(s):2573 - 2579  
Digital Object Identifier 10.1109/22.971652  
[AbstractPlus](#) | [References](#) | Full Text: [PDF\(216 KB\)](#) IEEE JNL

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